

Special Issue

Terahertz Imaging Technologies and Applications

Message from the Guest Editor

This Special Issue is devoted to terahertz imaging technologies and applications. However, considering that validating a hypothesis typically involves cross-checking, the use of combined approaches is also welcomed. In any case, the authors should demonstrate that the part of TIT is predominant in their works and directly contributes to the implementation of new ideas. Comprehensive reviews on imaging modalities, instrumentation, algorithms, and their potential applications will be especially welcomed, particularly in the transition from laboratory research to commercial case studies.

Guest Editor

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closed (30 December 2025)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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